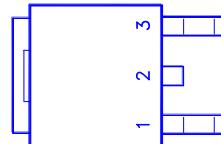
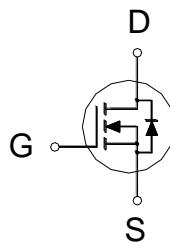


NIKO-SEM**N-Channel High Voltage Mode
Field Effect Transistor****P1160VD**
TO-252
Halogen-Free & Lead-Free**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
600V	410mΩ	11A



1. GATE
2. DRAIN
3. SOURCE

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	600	V
Gate-Source Voltage	V_{GS}	± 30	V
Continuous Drain Current ²	I_D	11	A
		7	
Pulsed Drain Current ¹	I_{DM}	40	
Avalanche Current ³	I_{AS}	3	A
Avalanche Energy ³	E_{AS}	180	mJ
Power Dissipation	P_D	54	W
		21	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		2.3	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	°C / W

¹Pulse width limited by maximum junction temperature.

²Ensure that the channel temperature does not exceed 150°C.

³ $V_{DD} = 50\text{V}$, $L = 40\text{mH}$, starting $T_J = 25^\circ\text{C}$.

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	600			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	2	3.4	4	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 30\text{V}$			± 100	nA
Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 600\text{V}, V_{GS} = 0\text{V}, T_C = 25^\circ\text{C}$			1	μA
		$V_{DS} = 480\text{V}, V_{GS} = 0\text{V}, T_C = 100^\circ\text{C}$			100	

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Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 5.5A$		356	410	$m\Omega$
Forward Transconductance ¹	g_{fs}	$V_{DS} = 10V, I_D = 5.5A$		10		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 100V, f = 250KHz$		749		pF
Output Capacitance	C_{oss}			50		
Reverse Transfer Capacitance	C_{rss}			4.6		
Effective Output Capacitance ⁴	$C_{o(er)}$	$V_{GS} = 0V, V_{DS} = 0 \text{ to } 480V$		37		
Total Gate Charge ²	Q_g	$V_{DD} = 480V, I_D = 5.5A, V_{GS} = 10V$		19.5		nC
Gate-Source Charge ²	Q_{gs}			3.8		
Gate-Drain Charge ²	Q_{gd}			7.5		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DD} = 300V, I_D = 5.5A, R_G = 25\Omega, V_{GS} = 10V$		21		nS
Rise Time ²	t_r			24		
Turn-Off Delay Time ²	$t_{d(off)}$			73		
Fall Time ²	t_f			21		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current ³	I_S	$I_F = 11A, V_{GS} = 0V$			11	A
Forward Voltage ¹	V_{SD}				1	V
Reverse Recovery Time	t_{rr}			230		nS
Reverse Recovery Charge	Q_{rr}			2		uC

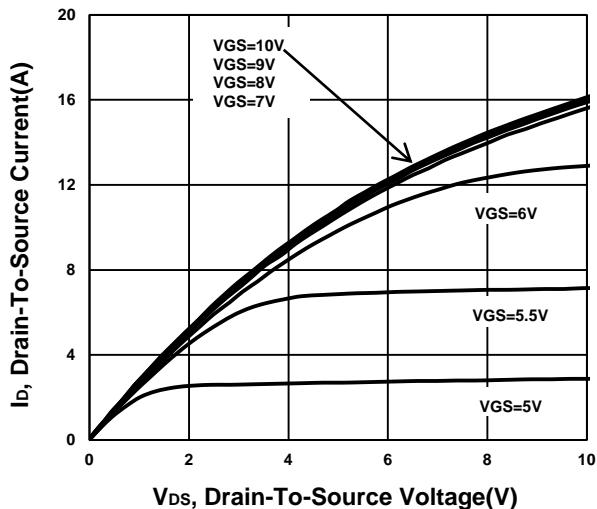
¹Pulse test : Pulse Width $\leq 380 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Pulse width limited by maximum junction temperature.⁴ $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% $V_{(BR)DSS}$.

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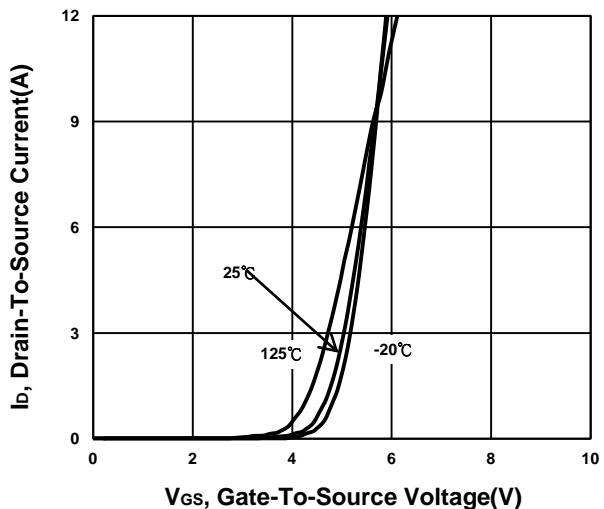
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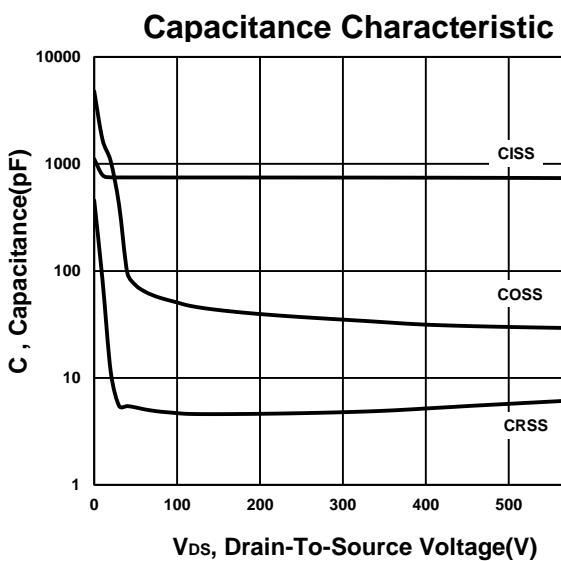
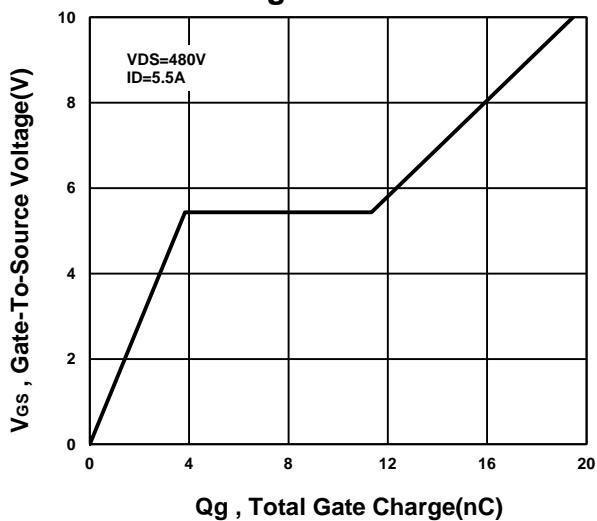
Output Characteristics



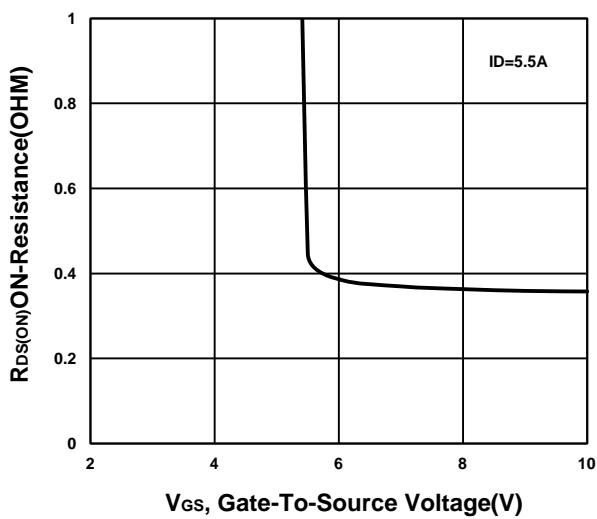
Transfer Characteristics



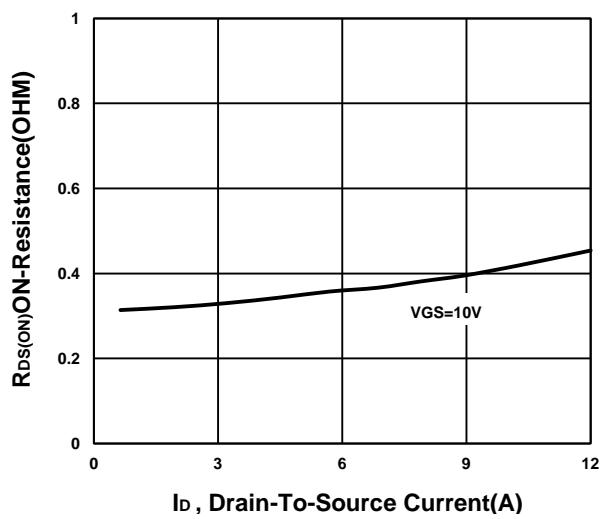
Gate charge Characteristics



On-Resistance VS Gate-To-Source Voltage



On-Resistance VS Drain Current



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